

**Notice of References Cited**

Application/Control No.

10/625,732

Applicant(s)/Patent Under  
Reexamination  
FUJIMOTO ET AL.

Examiner

Hiep T Nguyen

Art Unit

2187

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,611,903	08-2003	Fujimoto et al.	711/162
	B	US-6,725,293	04-2004	Nakayama et al.	710/36
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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